

Transverse Single-Spin
Asymmetry for inclusive and
diffractive process with $p^\uparrow + p$
collision at $\sqrt{s} = 200$ GeV

Xilin Liang

General Information

- Data set: run 15 pp transverse $\sqrt{s} = 200$ GeV ,fms stream
 - (production_pp200trans_2015)
- Production type: MuDst ; Production tag: P15ik
- Trigger for FMS : FMS small board sum, FMS large board sum and FMS-JP.
 - Trigger list: FMS-JP0, FMS-JP1, FMS-JP2, FMS-sm-bs1, FMS-sm-bs2, FMS-lg-bs1, FMS-lg-bs2, FMS-lg-bs3. (8 triggers)
- EM-jet reconstruction: Anti- k_T algorithm with $R=0.7$

Paper Information

- Title: Transverse Single-Spin Asymmetry for inclusive and diffractive process with $p^\uparrow + p$ collision at $\sqrt{s} = 200$ GeV
- PAs: Kenneth Barish, Carl Gagliardi, Latif Kabir, **Xilin Liang***
- Target journal: TBD
- Webpage and analysis note: TBD

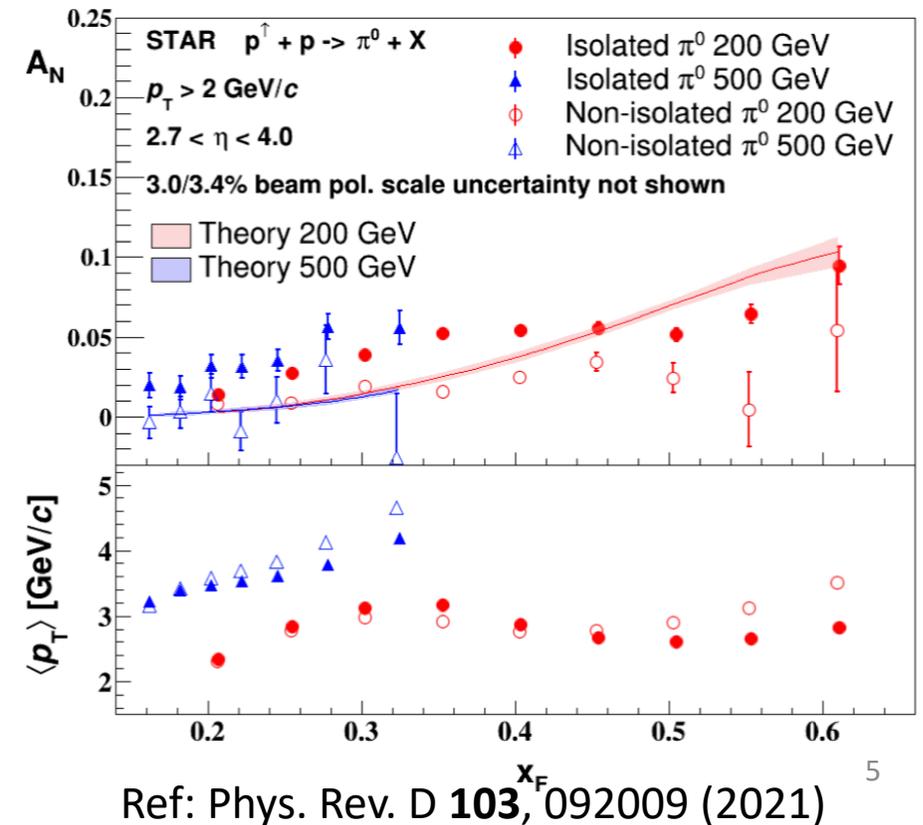
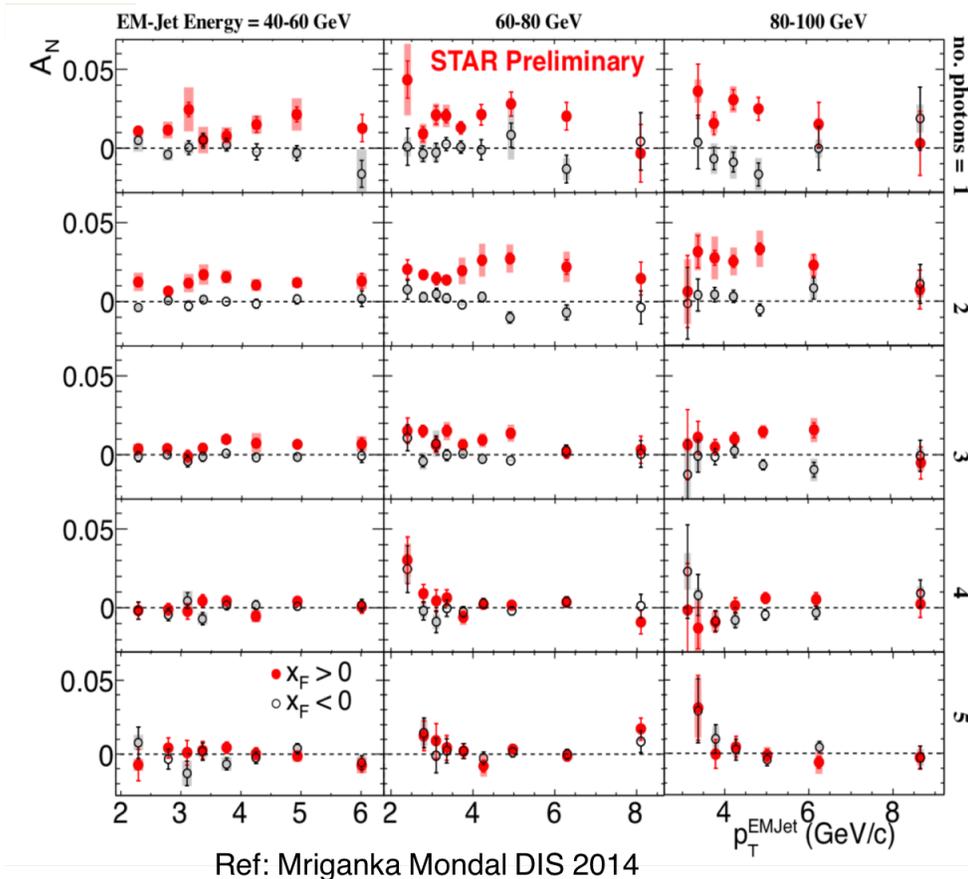
*Email: xilin.liang@email.ucr.edu

Abstract

- The STAR Collaboration reports the measurements of transverse single-spin asymmetry, A_N , for inclusive and diffractive electromagnetic jets (EM-jets) at center-of-mass energy of 200 GeV in transversely polarized proton-proton collisions in the pseudorapidity region of 2.6 to 4.1. The photon-multiplicity dependent (jetness) A_N results of inclusive EM-jets are investigated. It shows the A_N of lower jetness inclusive EM-jets is significantly larger than that of higher jetness inclusive EM-jets. The A_N of inclusive EM-jets is observed to increase with increasing Feynman x (x_F) regardless of the jetness of the inclusive EM-jets. For the diffractive EM-jets, the non-zero A_N is observed with 3.8-sigma significance. However, the A_N value is negative, which is opposite to the results for inclusive EM-jets A_N . The diffractive process is not the possible explanation for sources of larger A_N for lower jetness inclusive EM-jets or isolated π^0 .

Motivation

- Explore inclusive EM-jet A_N separated by different photon multiplicity.
- Diffractive process may play a role to explain large A_N .
 - A_N decreases with Increasing number of photons in EM jets.
 - Isolated π^0 events have larger A_N .



Diffraction process channels

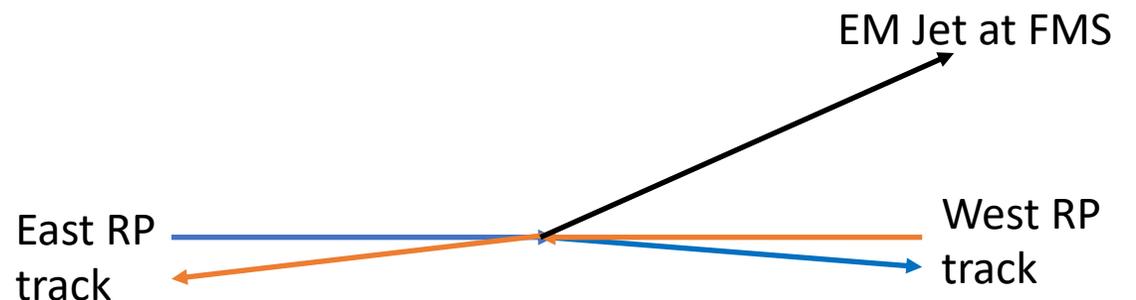
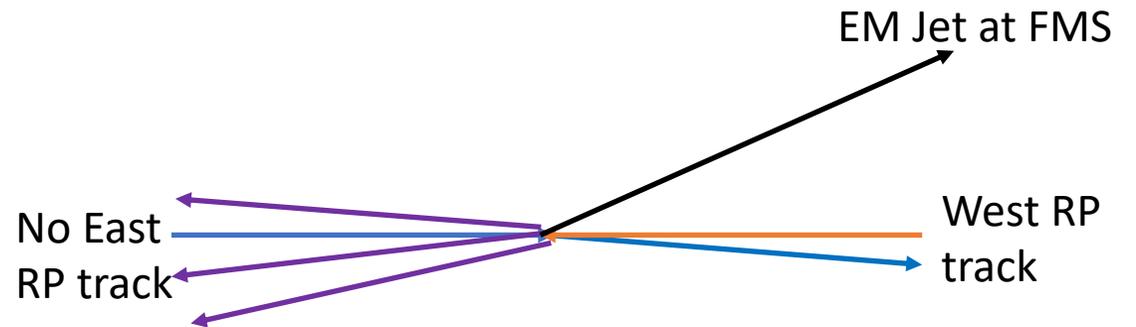
2 diffractive channels are considered. They all contain only 1 west RP track.

Single diffractive event: Only 1 proton track on west side RP.

Require: sum of west side tracks energy (proton + EM Jet) less than beam energy

Double diffractive event: Only 1 proton track on east side RP and only 1 proton track on west side RP.

Require: sum of west side tracks energy (proton + EM Jet) less than beam energy



Event selection and corrections

- **FMS**
 - 8 Triggers (avoid ring of fire) , veto on FMS-LED
 - bit shift, bad / dead / hot channel masking (include fill by fill hot channel masking)
 - Jet reconstruction: StJetMaker2015 , Anti-kT, $R < 0.7$, FMS tower energy > 2 GeV, $p_T > 1$ GeV/c for diffractive EM-jet ($p_T > 2$ GeV/c for inclusive EM-jet), FMS point as input
 - Apply energy correction.
- **Only allow acceptable beam polarization (up/down).**
- **Vertex** (Determine vertex z priority according to TPC , VPD, BBC.)
 - Vertex $|z| < 80$ cm
- **Roman Pot and Diffractive process (diffractive EM-jet only)**
 - Acceptable cases:
 1. Only 1 west RP track + no east RP track
 2. Only 1 east RP track + only 1 west RP track
 - RP track must be good track:
 - a) Each track hits > 6 planes
 - b) $-2 < \theta_x < 2$ mrad , $1.5 < |\theta_y| < 4.5$ mrad
 - Sum of west RP track energy and all EM Jet energy (see detail in table)
- **BBC ADC sum cuts (diffractive EM-jet only):**
 - West Large BBC ADC sum < 60 and West Small BBC ADC sum < 100

Corrections:

EM-jet energy correction and Underlying Event energy correction

x_F	E sum Cut
0.1 - 0.15	$E_{\text{sum}} < 108$ GeV
0.15 - 0.2	$E_{\text{sum}} < 108$ GeV
0.2 - 0.25	$E_{\text{sum}} < 110$ GeV
0.25 - 0.3	$E_{\text{sum}} < 110$ GeV
0.3 - 0.45	$E_{\text{sum}} < 115$ GeV

Technical details

- Event selection
- Corrections:
 - Energy correction: based on simulations, apply correction from detector level to particle level.
 - Underlying correction: use off-axis cone method.
- A_N extraction: cross ratio method.

Systematic uncertainty

- Inclusive EM-jet A_N :
 - Event misidentification (from Unfolding)
 - Background uncertainty: pile-up, Abort gap, Ring of Fire, Underlying events.
 - Polarization uncertainty
 - Energy / p_T uncertainty: calibration uncertainty, energy / p_T correction, uncertainty due to radiation damage.
- Diffractive EM-jet A_N :
 - Background uncertainty: Ring of Fire, energy sum cuts, BBC cuts.
 - Polarization uncertainty
 - Energy / p_T uncertainty: calibration uncertainty, energy / p_T correction, uncertainty due to radiation damage.

Fig. 1: A_N for inclusive EM-jet separated by EM-jet energy and jetness

- Fig. 1: Measurement of transverse single-spin asymmetry for three different jetness and three different EM-jet energy region, expressing as a function of EM-jet transverse momentum. The statistical uncertainties are shown in bar and the systematic uncertainties are shown in box. The lowest panel shows the average $|x_F|$.

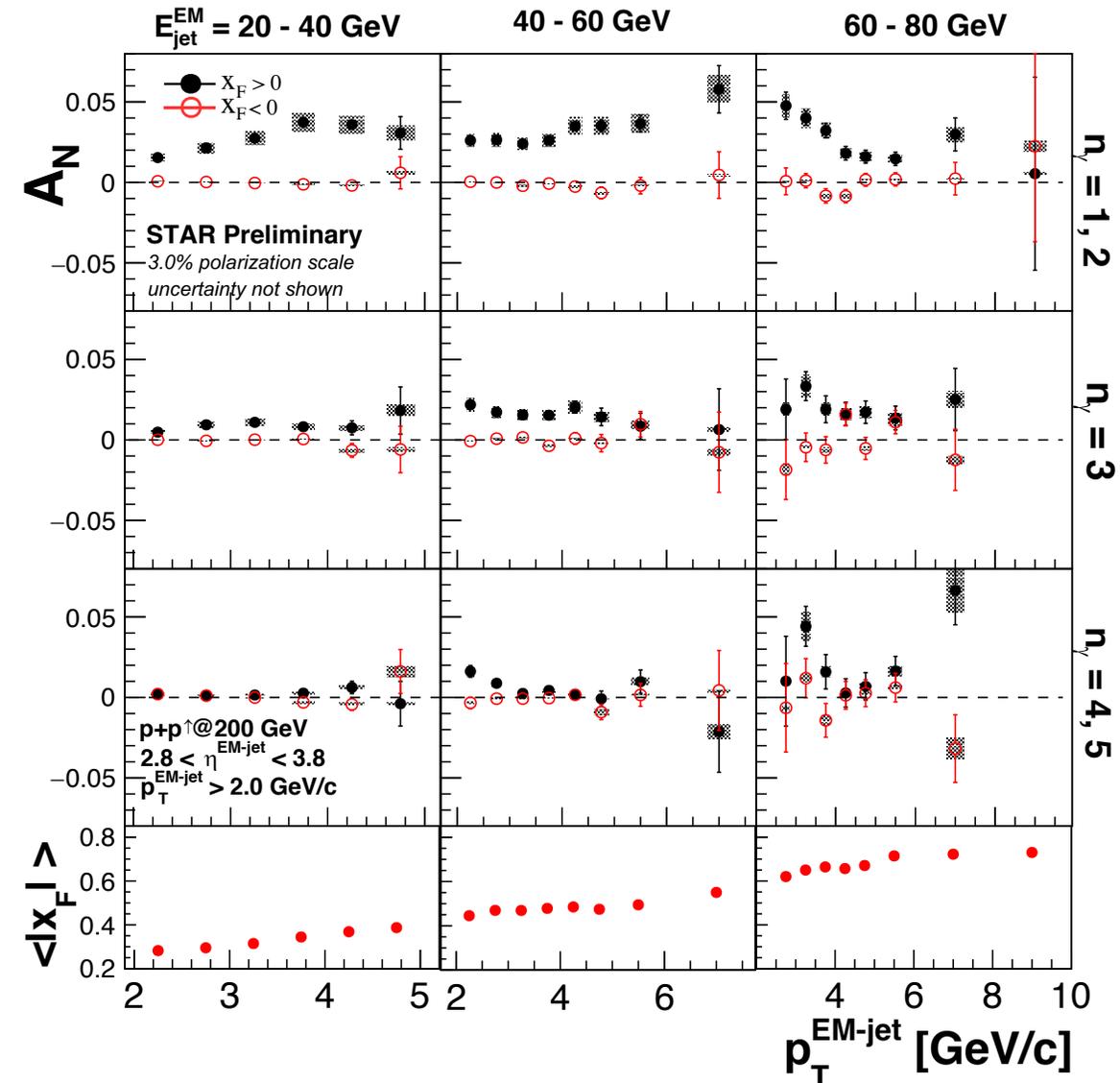


Fig. 2: A_N for inclusive EM-jet vs x_F

- Fig. 2: Measurement of transverse single-spin asymmetry for three different jetness as a function of x_F . The statistical uncertainties are shown in bar and the systematic uncertainties are shown in box.

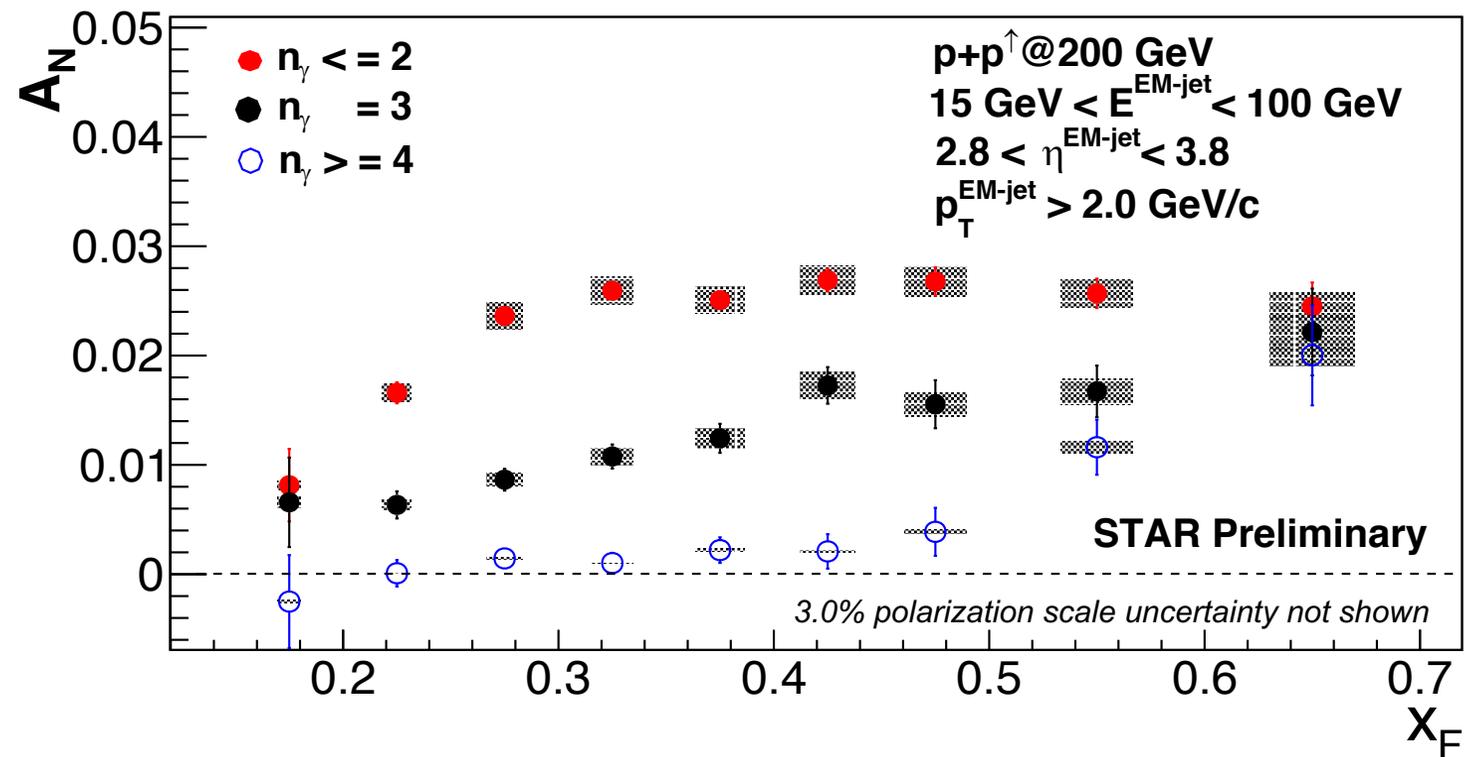
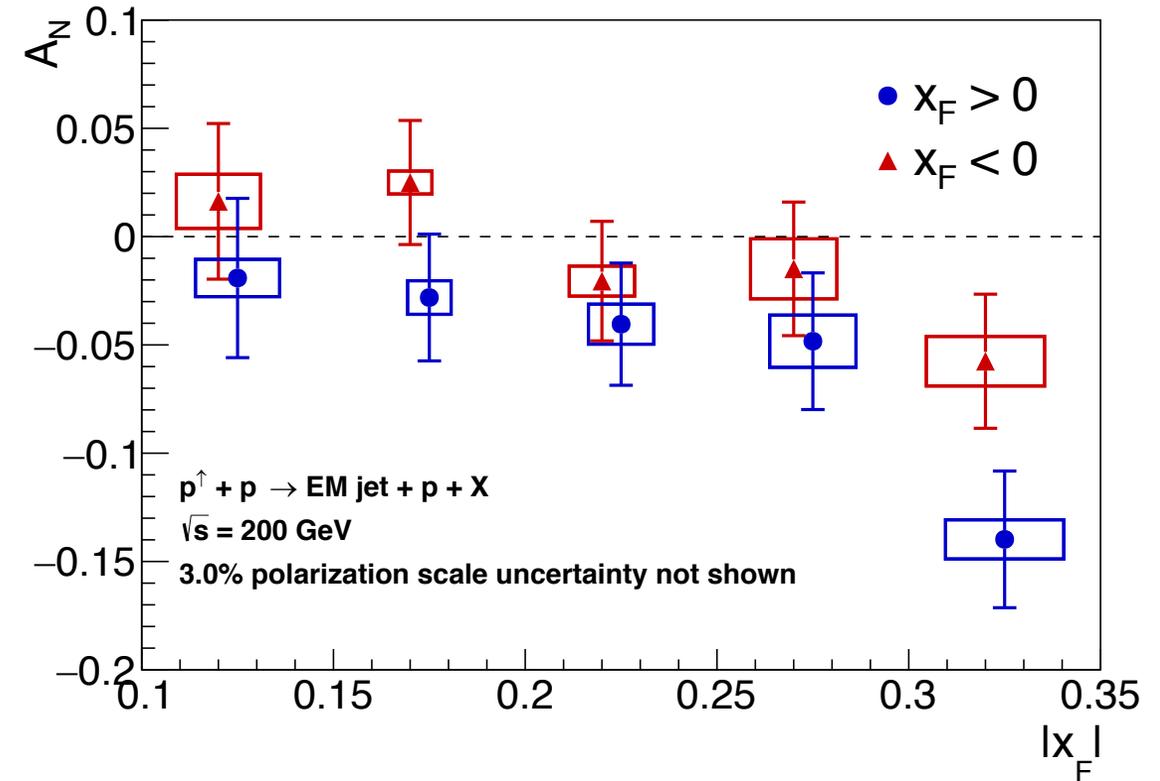


Fig. 3: A_N for diffractive EM-jet

- Fig. 3: Measurement of transverse single-spin asymmetry for diffractive EM-jet as a function of x_F . The statistical uncertainties are shown in bar and the systematic uncertainties are shown in box. The rightmost blue (red) points are for $0.3 < x_F < 0.45$ ($-0.45 < x_F < -0.3$). All the red points shift -0.005 in x-axis.



Back up

Transverse single spin asymmetry (A_N) calculation

- We use **cross ratio** method to calculate the diffractive EM Jet A_N at FMS.

- Raw A_N :
$$\varepsilon = \frac{\sqrt{N^\uparrow(\phi)N^\downarrow(\phi+\pi)} - \sqrt{N^\downarrow(\phi)N^\uparrow(\phi+\pi)}}{\sqrt{N^\uparrow(\phi)N^\downarrow(\phi+\pi)} + \sqrt{N^\downarrow(\phi)N^\uparrow(\phi+\pi)}} \approx pol * A_N * \cos(\phi)$$

- Plot A_N as a function of X_F , or p_T ($x_F = \frac{E_{EM\ jet}}{E_{Beam}}$)
- Divide full ϕ range $[-\pi, +\pi]$ into 16 bins.

